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## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	A01	3,354,022	11/1967	Dettre et al.	<del>          </del>		
	A02						
	A03						
	A04						
	A05						
	A06						
	A07						
	A08						
	A09						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
<i>Handwritten mark</i>	B01	0 772 514 B1	05/1997	EPO				
	B02							
	B03							
	B04							
	B05							

**OTHER REFERENCES** *(Including Author, Title, Date, Pertinent Pages, Etc.)*

✓	C01	"Elektronenmikroskopie" by Flegler et al., 195 Spektrum Akademischer Verlag Heidelberg
	C02	
	C03	

**EXAMINER**

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.